

Application No.

Applicant(s)

09/839,416 Examiner ISHIDA, KOZO

Art Unit

Mohamed Charioui

2857

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SEARCHED				
Class	Subclass	Date	Examiner	
702	64, 65, 110, 183	3/18/2004	MC	
702	118-125	3/19/2004	МС	
714	724-727	3/19/2004	MC	
324	73.1	3/19/2004	МС	
324	763-765	3/19/2004	МС	
Search	updated	9/10/2004	MC	
714	30, 733	9/10/2004	МС	
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
702	120	9/10/2004	МС		
714	30	9/10/2004	МС		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East: (semiconductor or semiconductors or "integrated circuits" or "IC") and "shift register" and ((selector or selecting or	3/18/2004	МС		
selected or selects) with buffer) and "flip-flop" and (tester or testing or tested or tests)	3/18/2004	мс		
East: ((tristate near (buffer or buffers)) with (impedance or impedances or resistor or resictors) and ("flip-flop" or	3/19/2004	мс		
"flip-flops")	3/19/2004	МС		
IEEE: search by inventor's name.	3/19/2004	МС		
Text search updated	9/10/2004	МС		